

Features

- Lead free versions available
- RoHS compliant (lead free version)*
- Bidirectional EMI filtering
- ESD protection
- Protects two audio lines

Applications

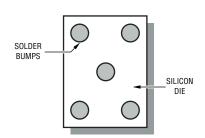
- Cell phones
- PDAs and notebooks
- Digital cameras
- MP3 players and GPS

2FAM-C5R - Integrated Passive & Active Device using CSP

General Information

The 2FAM-C5R device, manufactured using Thin Film on Silicon technology, provides ESD protection and EMI filtering for the audio port of portable electronic devices such as cell phones, modems and PDAs. The device incorporates two low pass filter channels where each channel has a series 10 ohm resistor assuring a minimum of -25 dB attenuation from 800 MHz to 3 GHz. The device is suitable for EMI filtering of GSM, CDMA, W-CDMA, WLAN and Bluetooth frequencies.

Each internal and external port of the two channels includes a TVS diode for ESD protection. The ESD protection provided by the component enables a data port to withstand a minimum ±8 KV Contact / ±15 KV Air Discharge per the ESD test method specified in IEC 61000-4-2. The device measures 1.00 mm x 1.33 mm and is available in a 5 bump CSP package intended to be mounted directly onto an FR4 printed circuit board. The CSP device meets typical thermal cycle and bend test specifications without the use of an underfill material.

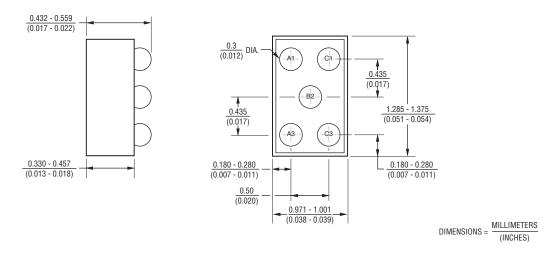


Electrical & Thermal Characteristics

Electrical Characteristics (T _A = 25 °C unless otherwise noted)	Symbol	Minimum	Nominal	Maximum	Unit
Per Line Specification					
Resistance	R	8	10	12	Ω
Capacitance @ 0 V 1 MHz	С	32	40	48	pF
Rated Standoff Voltage	V _{wm}		5.0		V
Breakdown Voltage @ 1 mA	V_{BR}	6.0			V
Forward Voltage @ 10 mA	V _F		0.8		V
Leakage Current @ 3.3 V	I _R		0.1	0.5	μΑ
Filter Attenuation @ 800 - 3000 MHz	S21	-25	-30		dB
ESD Protection: IEC 61000-4-2 Contact Discharge Air Discharge		±8 ±15			kV kV
Thermal Characteristics					
(T _A = 25 °C unless otherwise noted)					
Operating Temperature Range	T _J	-40	25	+85	°C
Storage Temperature Range	T _{STG}	-55	25	+150	°C
Power Dissipation Per Resistor	P _D			100	mW

Mechanical Characteristics

This is a silicon-based device and is packaged using chip scale packaging technology. Solder bumps, formed on the silicon die, provide the interconnect medium from die to PCB. The bumps are arranged on the die in a regular grid formation. The grid pitch is 0.5 mm and the dimensions for the packaged device are shown below.



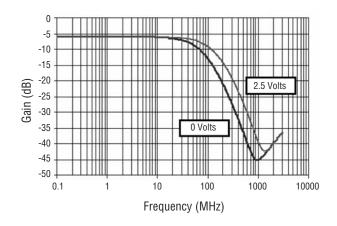
Reliability Data

Reliability data is gathered on an ongoing basis for Bourns® Integrated Passive and Active Devices.

"Package level" testing of the integrity of the solder joint is carried out on an independent Daisy-Chain test device. A 25-Pin Daisy Chain component is available from Bourns for this purpose (part number 2TAD-C25R). This is a 5 x 5 array featuring 0.5 mm pitch solder bumps. The Distance to Neutral Point (DNP) on that component is larger than that of the 2FAM-C5R and is thus deemed suitable for Thermal Cycle testing.

"Silicon level" reliability performance is based on similarity to other integrated passive CSP devices from Bourns.

Frequency Response

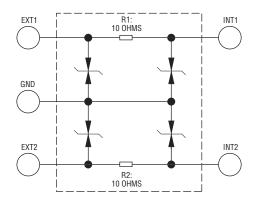


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Block Diagram

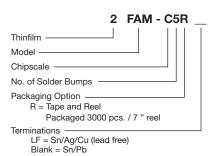
The CSP device block diagram below includes the pin names and basic electrical connections associated with each channel.



PCB Design and SMT Processing

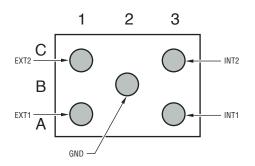
Please consult the "Bourns Design Guide Using CSP" for notes on PCB design and SMT Processing.

How to Order



Device Pin Out

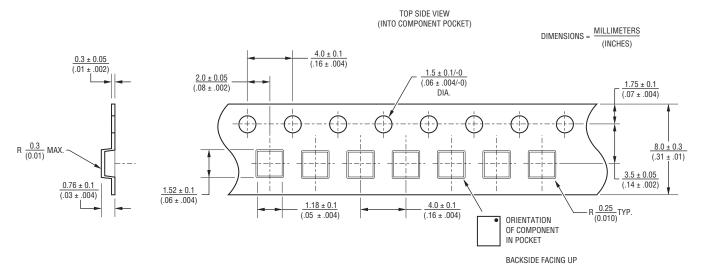
The pin-out for the device is shown below with the bumps facing up.



Pin Out	Function	Pin Out	Function
A1	EXT1	A3	INT1
C1	EXT2	C3	INT2
B2	GND		

Packaging

The surface mount product is packaged in an 8 mm x 4 mm Tape and Reel format per EIA-481 standard.





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